

Notice of References Cited	Application/Control No. 10/524,227	Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
	Examiner Linh T. Nguyen	Art Unit 2652	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0057704	03-2004	Katsuo et al.	386/125
*	B	US-2003/0180031	09-2003	Kikuchi et al.	386/46
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 11118998	03-2000	Europe	Watanabe et a.	G11B 20/12
	O	JP 2002218398 A	08-2002	Japan	YABANETA et al.	H04N 05/92
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.